

Notice of References Cited	Application/Control No. 10/582,330		Applicant(s)/Patent Under Reexamination SUMIYA, HITOSHI	
	Examiner SHENG HAN		Art Unit 1793	Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-2003/0039603	02-2003	Meng, Yue	423/446
*	B	US-3,148,161	09-1964	WENTORF JR ROBERT H et al.	252/502
	C	US-			
	D	US-			
	E	US-			
	F	US-			
	G	US-			
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	I					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	Bernard, M. et al. "Non-Destructive Determination of the boron concentration of heavily doped metallic diamond thin films from Raman Spectroscopy." Diamond and Related Materials 13 (2004) 282-286
	V	
	W	
	X	

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.